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# Lecture 2: CMOS Fabrication

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# Agenda

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- **Last module:**
  - Introduction to the course
  - How a transistor works
  - CMOS transistors
  
- **This module:**
  - CMOS Fabrication

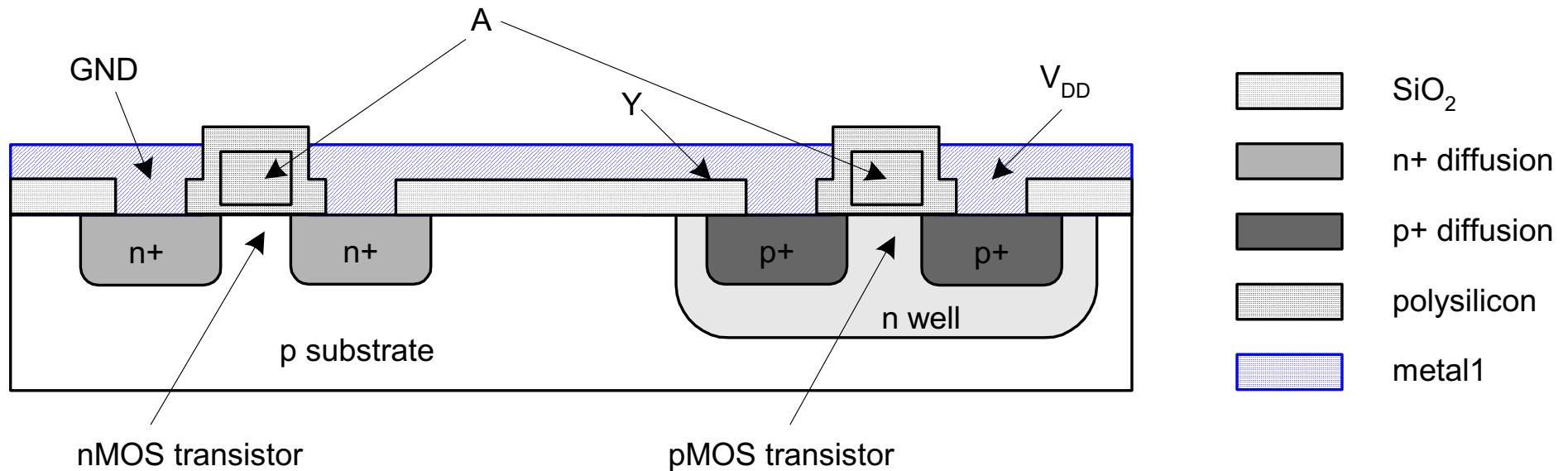
# CMOS Fabrication

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- **CMOS transistors are fabricated on silicon wafers**
- **Lithography process has been the mainstream chip manufacturing process**
  - Similar to a printing press
  - See [Chris Mack's page](#) for a nice [litho tutorial](#)
- **On each step, different materials are deposited or etched**
- **Easiest to understand by viewing both top and cross-section of wafer in a simplified manufacturing process**

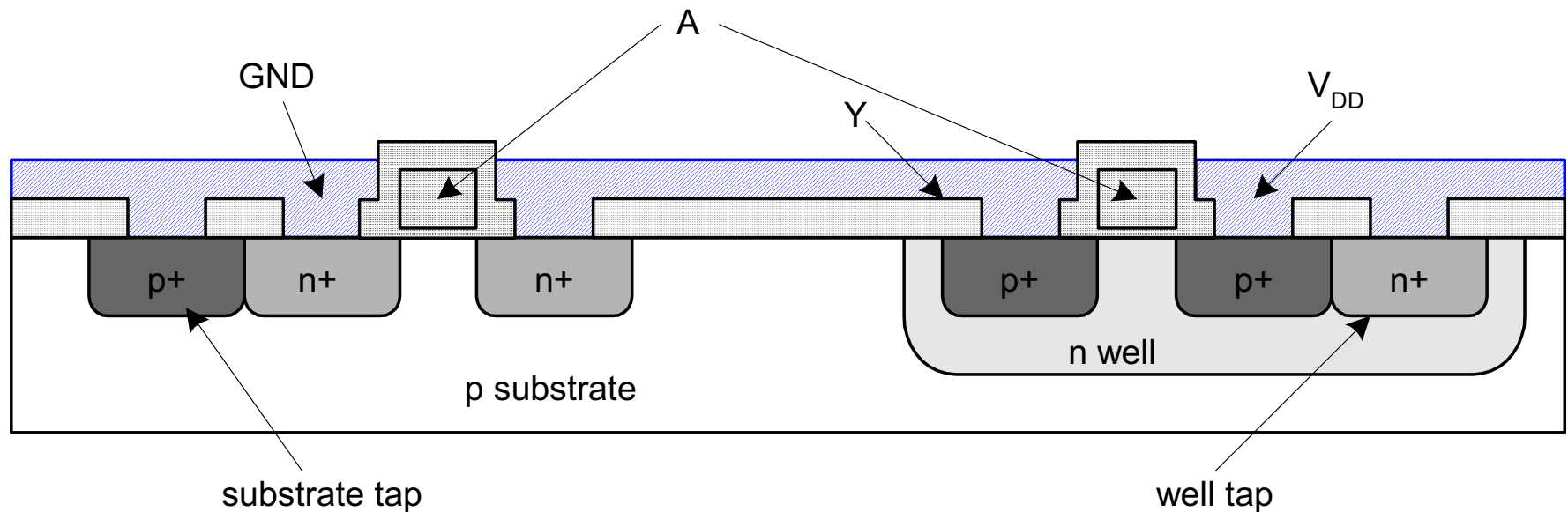
# Inverter Cross-section

- Typically use p-type substrate for nMOS transistors
- Requires n-well for body of pMOS transistors



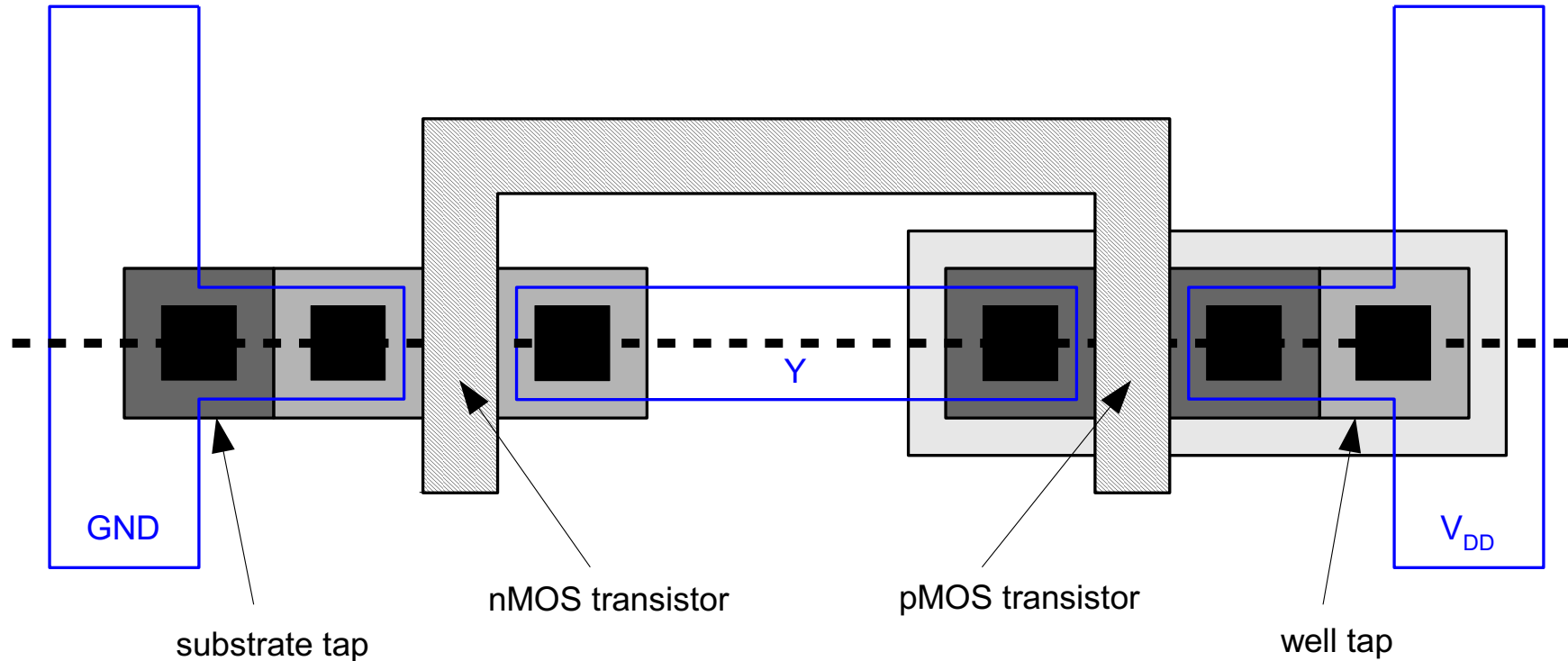
# Well and Substrate Taps

- Substrate must be tied to GND, n-well to VDD
- Metal to lightly-doped semiconductor forms poor connection called Schottky Diode
- Use heavily doped well and substrate contacts / taps



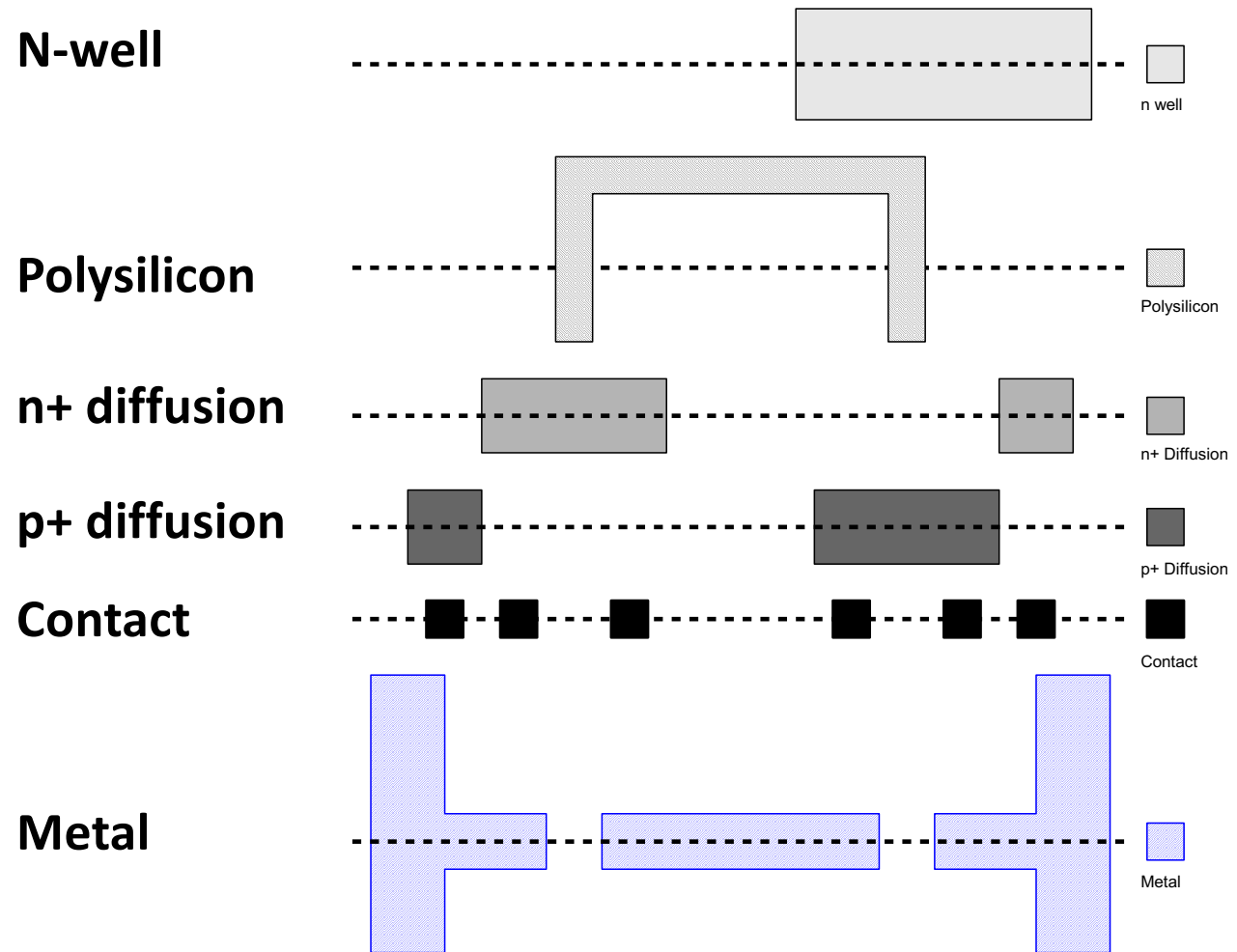
# Inverter Mask Set

- Transistors and wires are defined by masks
- Cross-section taken along dashed line



# Detailed Mask Views

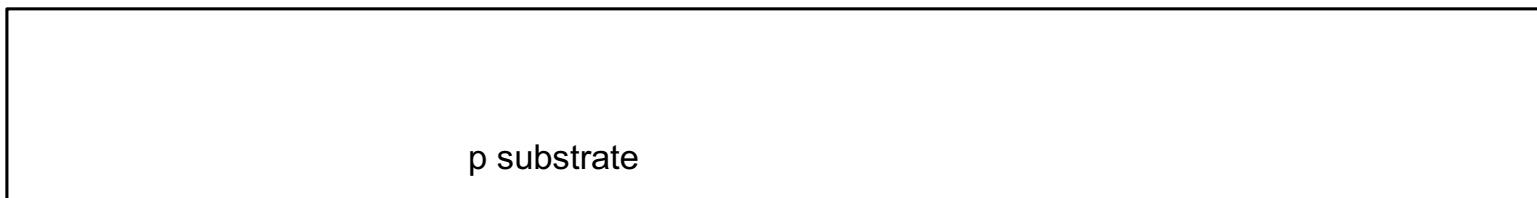
## Six masks to build simple inverter



# Fabrication Steps

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- **Start with blank wafer**
- **Build inverter from the bottom up**
- **First step will be to form the n-well**
  - Cover wafer with protective layer of  $\text{SiO}_2$  (oxide)
  - Remove layer where n-well should be built
  - Implant or diffuse n dopants into exposed wafer
  - Strip off  $\text{SiO}_2$

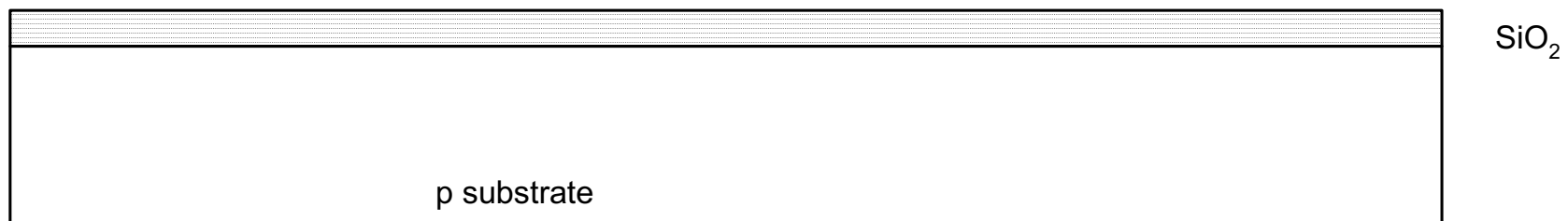




# Oxidation

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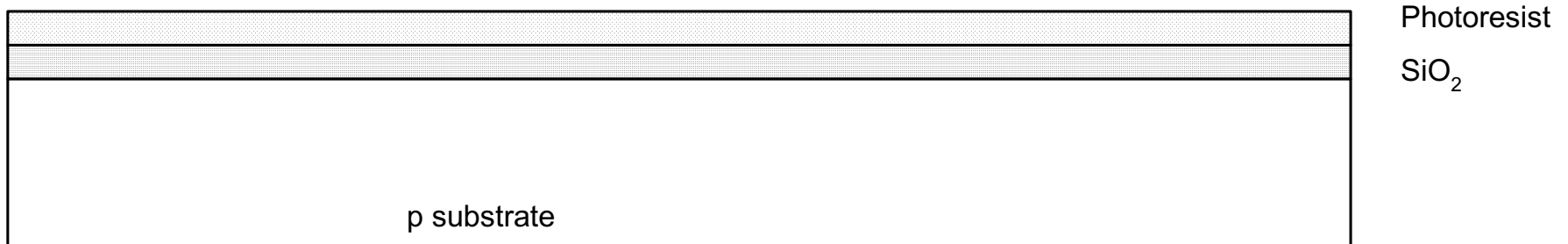
- **Grow  $\text{SiO}_2$  on top of Si wafer**
  - 900°C - 1200°C with  $\text{H}_2\text{O}$  or  $\text{O}_2$  in an oxidation furnace



# Photoresist

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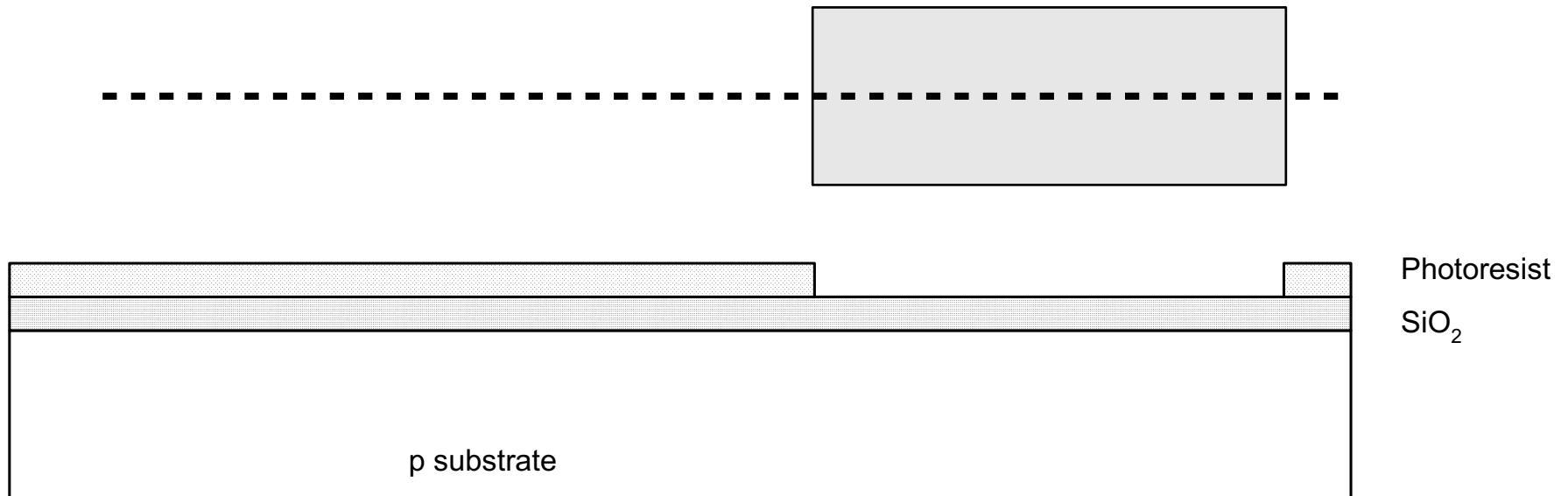
- **Spin on photoresist**
  - Photoresist is a light-sensitive organic polymer
  - Softens where exposed to light



# Lithography

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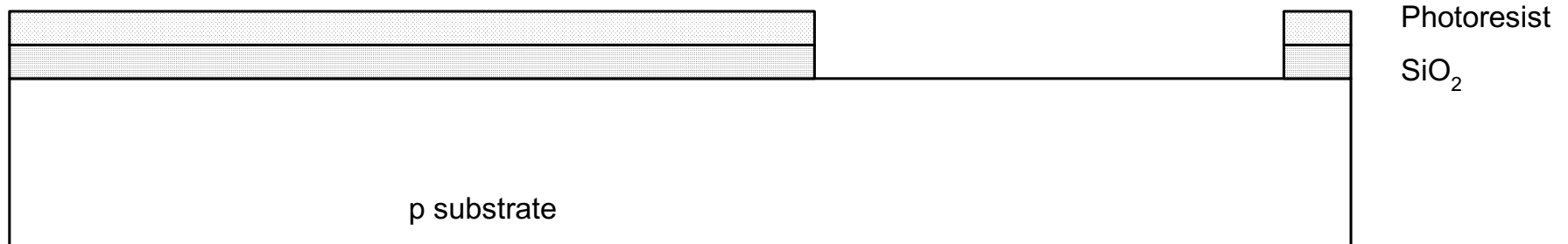
- Expose photoresist through n-well mask
- Strip off exposed photoresist



# Etch

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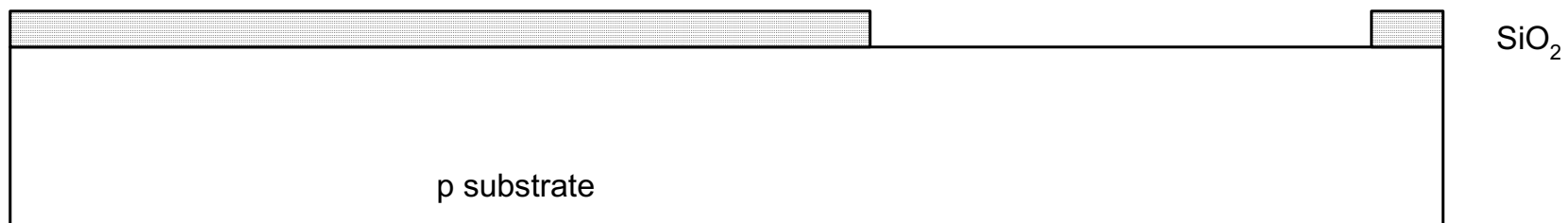
- **Etch oxide with hydrofluoric acid (HF)**
  - Seeps through skin and eats bone; nasty stuff!!!
- **Only attacks oxide where resist has been exposed**



# Strip Photoresist

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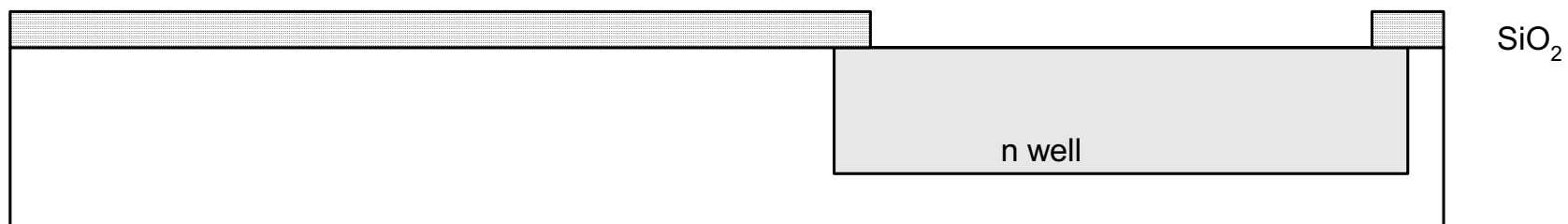
- **Strip off remaining photoresist**
  - Old days we used a mixture of nitric and sulphuric acids called piranah etch
  - Now we use a plasma etch which is much safer (and greener).
- **Necessary so resist doesn't melt in the next step**



# n-Well

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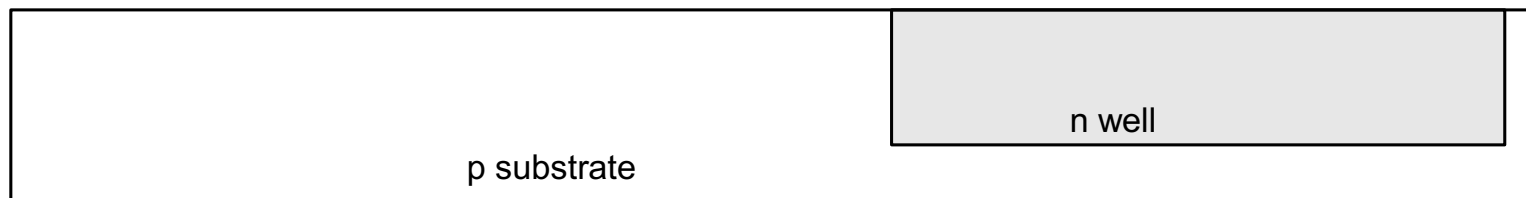
- **n-Well formed with diffusion or ion implant**
- **Diffusion**
  - Place wafer in furnace with Arsine ( $\text{AsH}_3$ ) gas
  - Heat until As atoms diffuse into exposed Si
- **Ion Implantation**
  - Blast wafer with beam of As ions
  - Ions blocked by  $\text{SiO}_2$ , only enter exposed Si



# Strip Oxide

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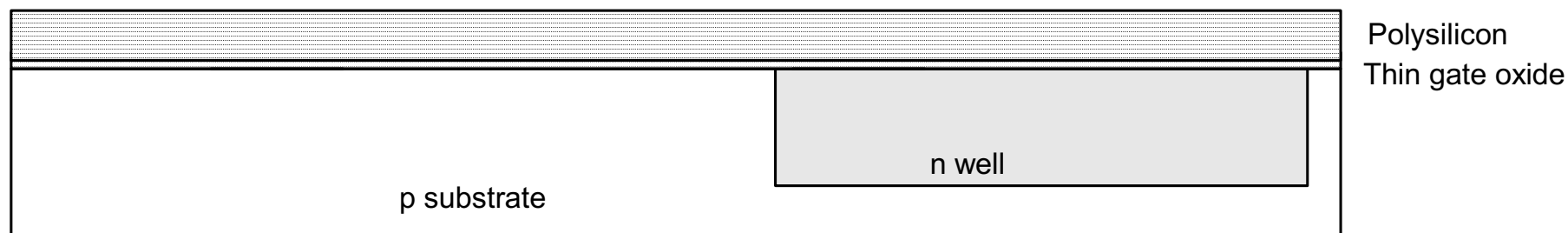
- Strip off the remaining oxide using HF
- Back to bare wafer with n-well
- Subsequent steps involve similar series of steps



# Polysilicon

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- **Grow/deposit very thin layer of gate oxide**
  - $< 20 \text{ \AA}$  (6-7 atomic layers)
- **Chemical Vapor Deposition (CVD) of Si layer**
  - Place wafer in furnace with Silane gas ( $\text{SiH}_4$ )
  - Forms many small crystals called polysilicon
  - Heavily doped to be good conductor

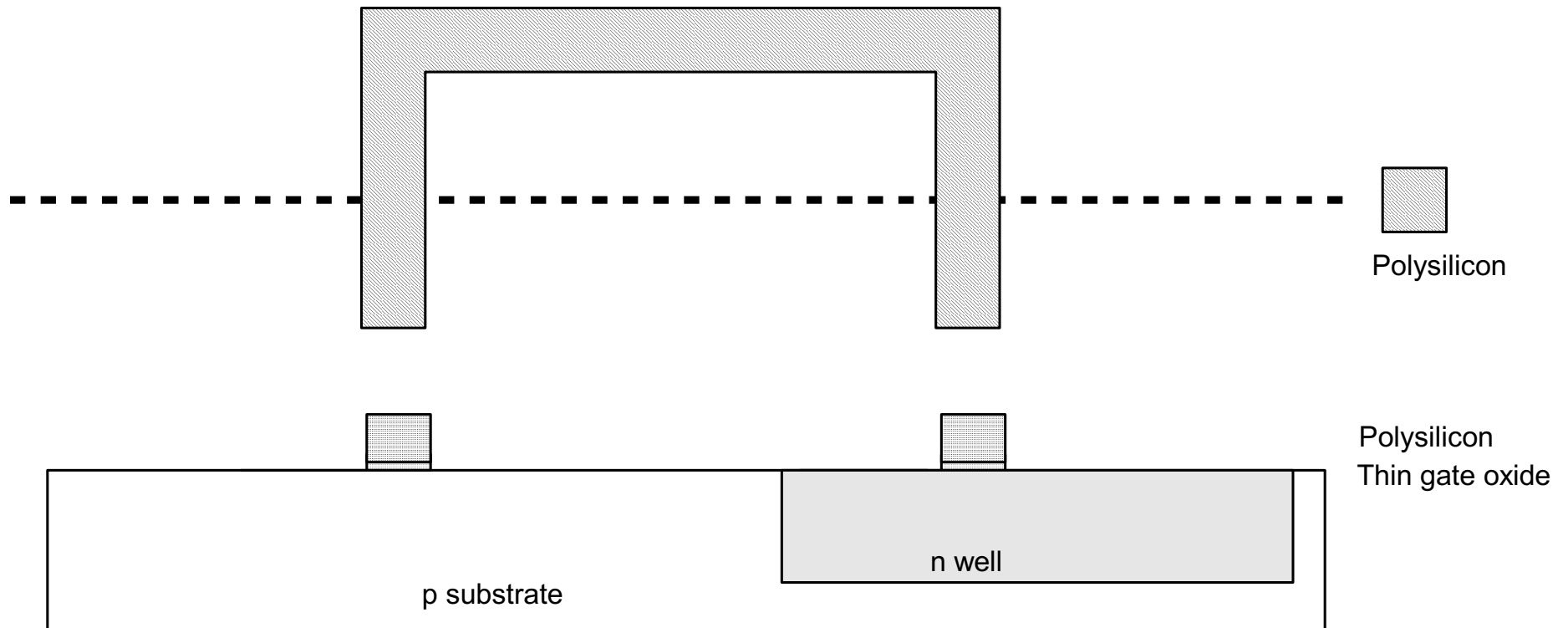


**Trend towards metal gates and rare earth (Hf, etc.) oxides  
in nanometer-scale processes**



# Polysilicon Patterning

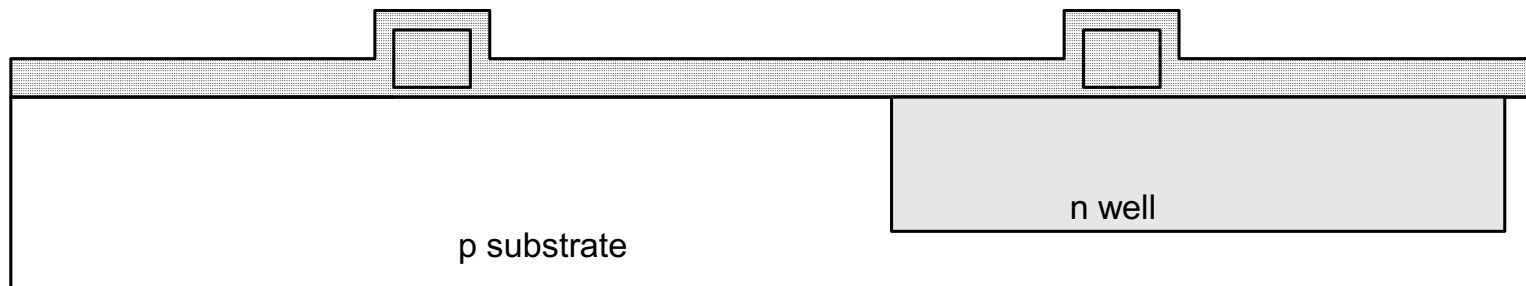
- Use same lithography process to pattern polysilicon



# Self-Aligned Process

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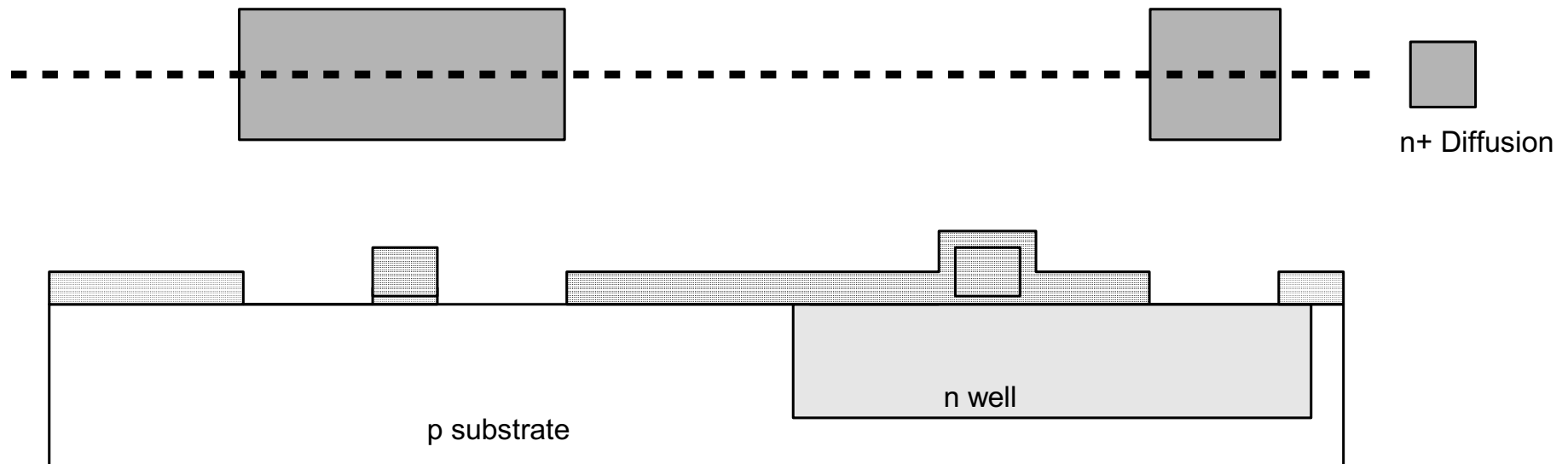
- Use oxide and masking to expose where n+ dopants should be diffused or implanted
- N-diffusion forms nMOS source, drain, and n-well contact



# N-diffusion

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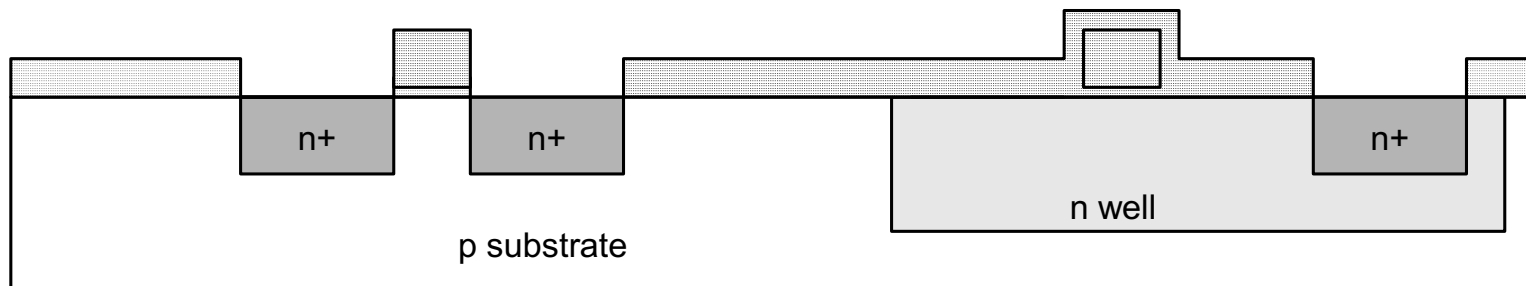
- Pattern oxide and form n+ regions
- *Self-aligned process* - gate blocks diffusion
- Polysilicon is better than metal for self-aligned gates because it doesn't melt during later processing



# N-diffusion, Cont' d

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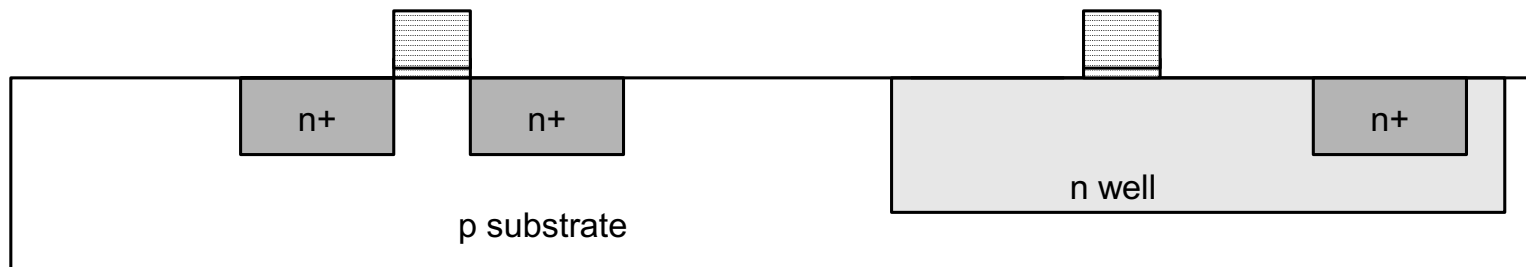
- Historically dopants were diffused
- Usually ion implantation today
- But regions are still called diffusion



# N-diffusion, Cont' d

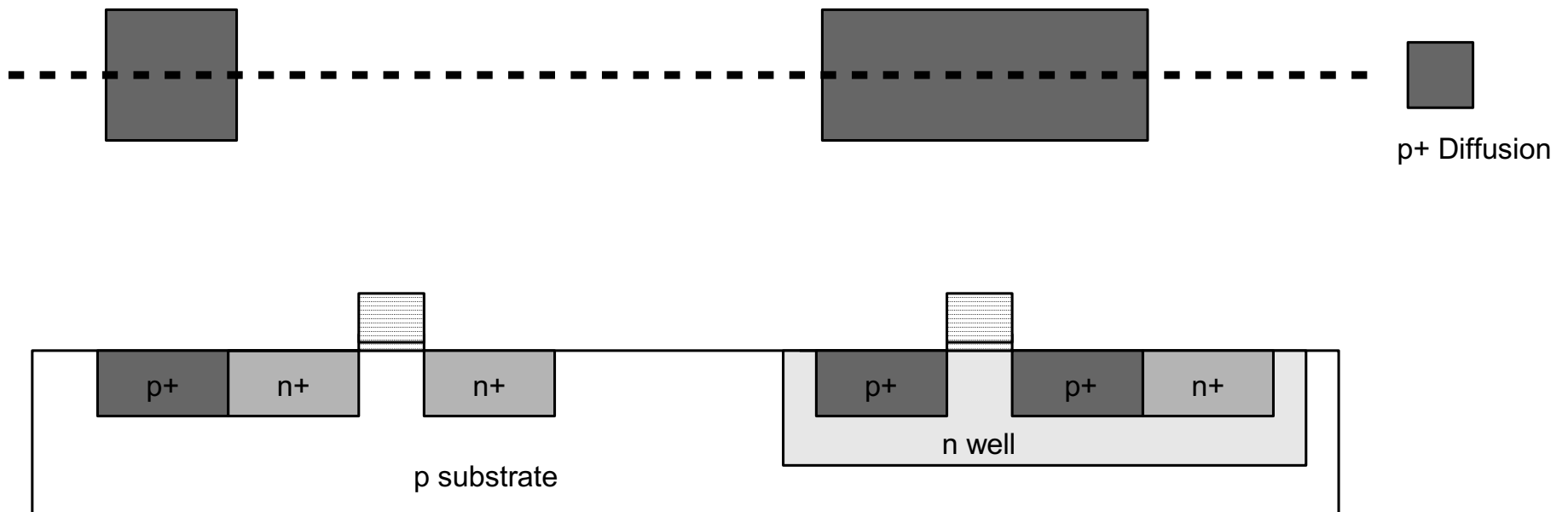
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- Strip off oxide to complete patterning step



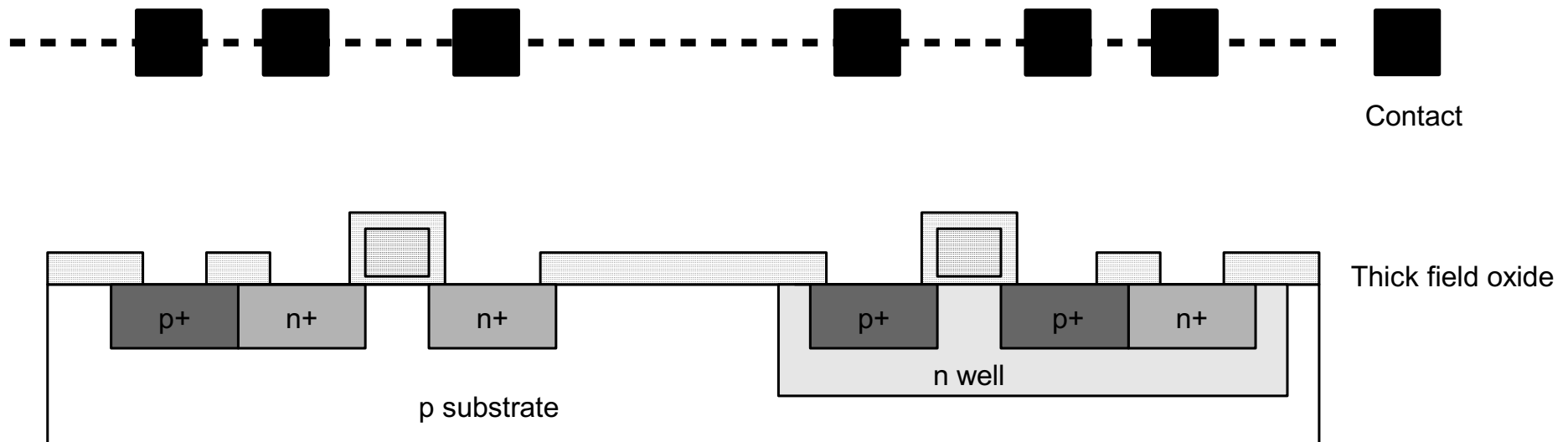
# P-Diffusion

- Similar set of steps form p+ diffusion regions for pMOS source and drain and substrate contact



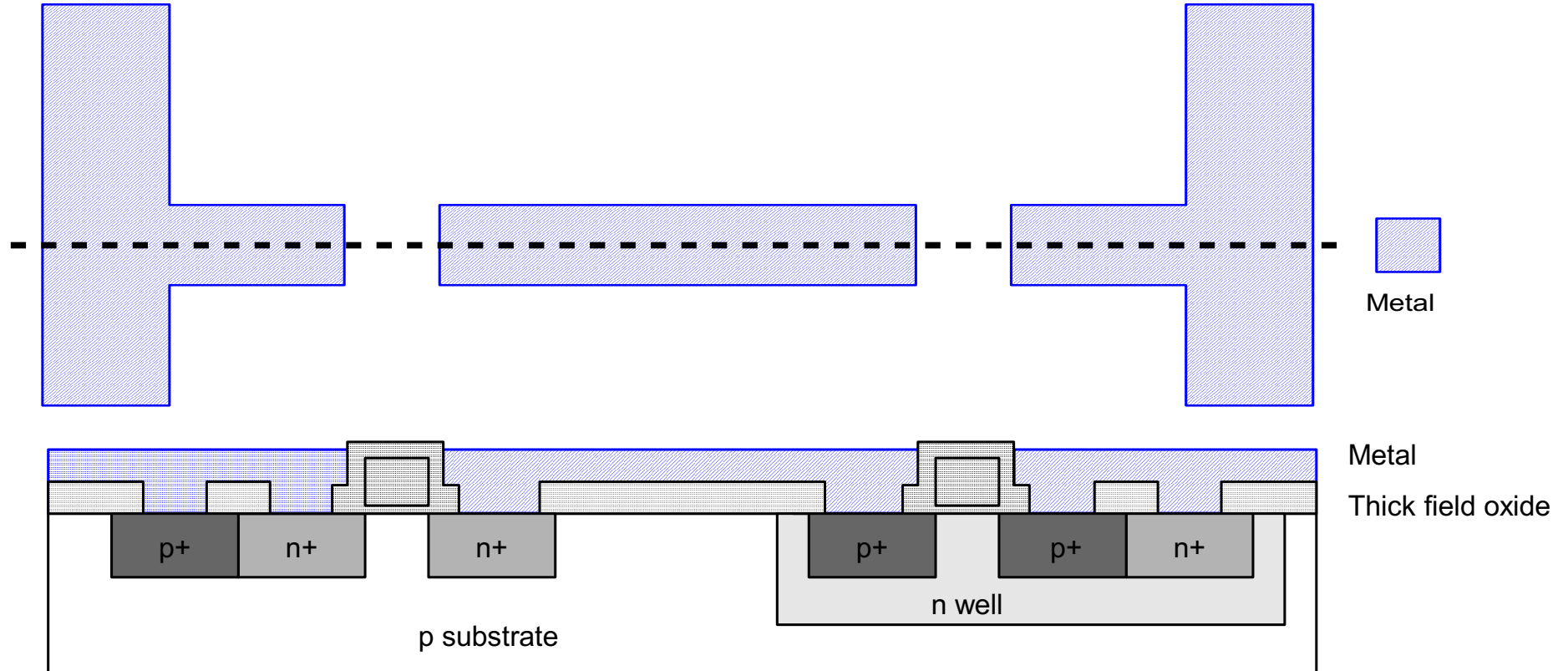
# Contacts

- Now we need to wire together the devices
- Cover chip with thick field oxide
- Etch oxide where contact cuts are needed



# Metallization

- Sputter on aluminum over whole wafer
- Pattern to remove excess metal, leaving wires

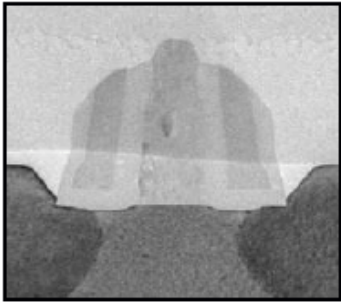




# Intel's 2-Year Technology Cadence

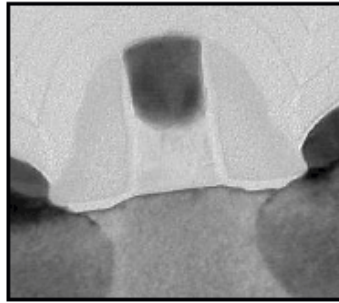
90 nm

2003



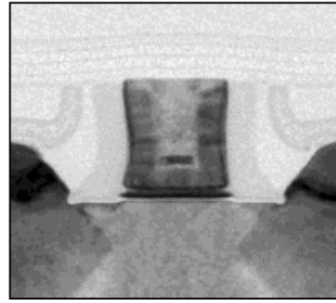
65 nm

2005



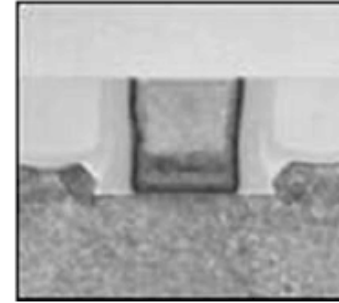
45 nm

2007



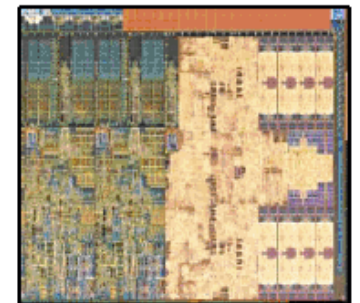
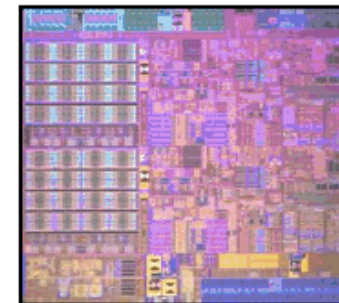
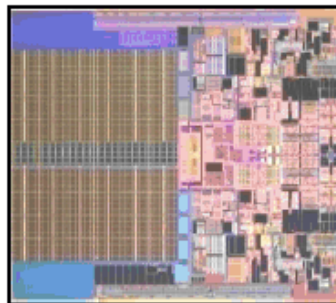
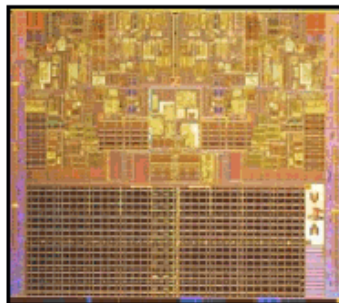
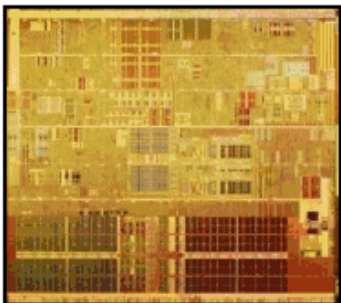
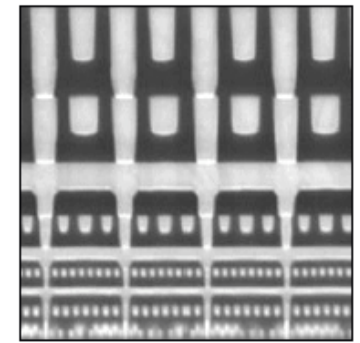
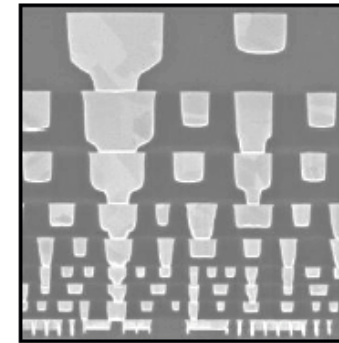
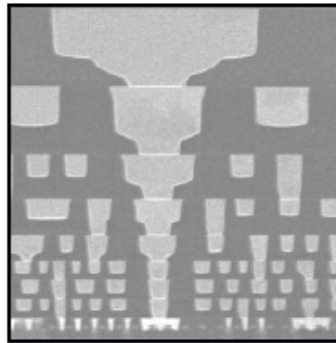
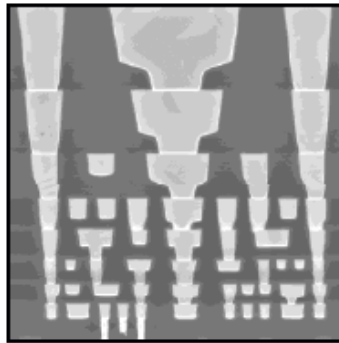
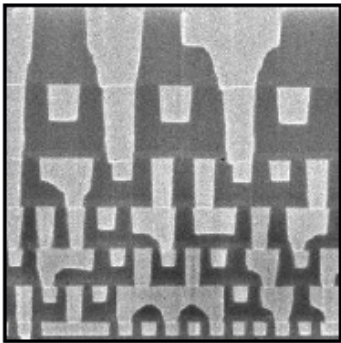
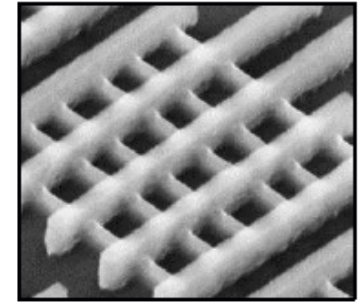
32 nm

2009



22 nm

2011



•Source: Mark Bohr, Intel Corporation

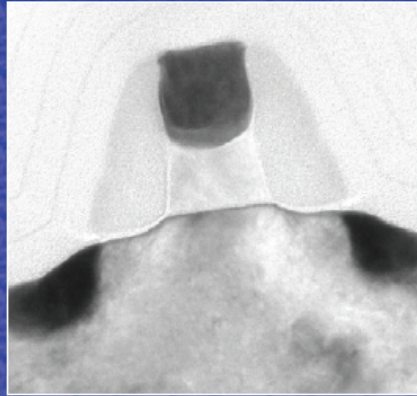
# MOBILITY IMPROVEMENT

High Performance

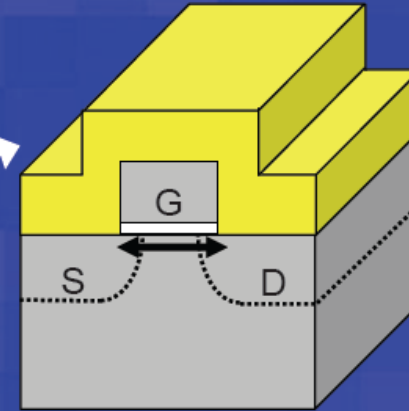
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## Strained Silicon Transistors

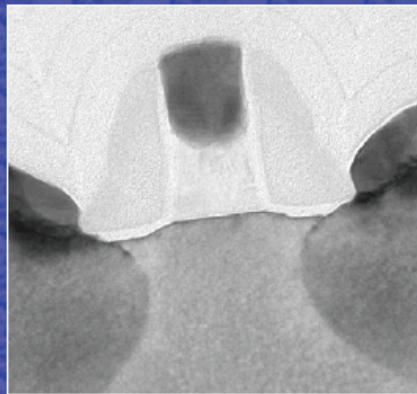
NMOS



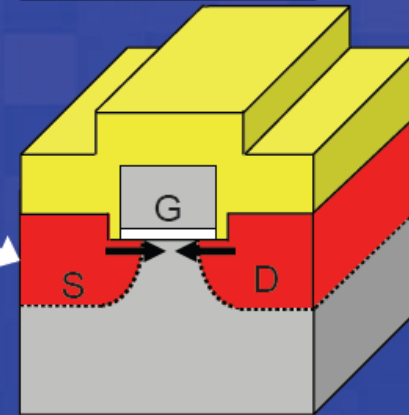
Si<sub>3</sub>N<sub>4</sub>  
Cap Layer



PMOS



SiGe  
Source-Drain



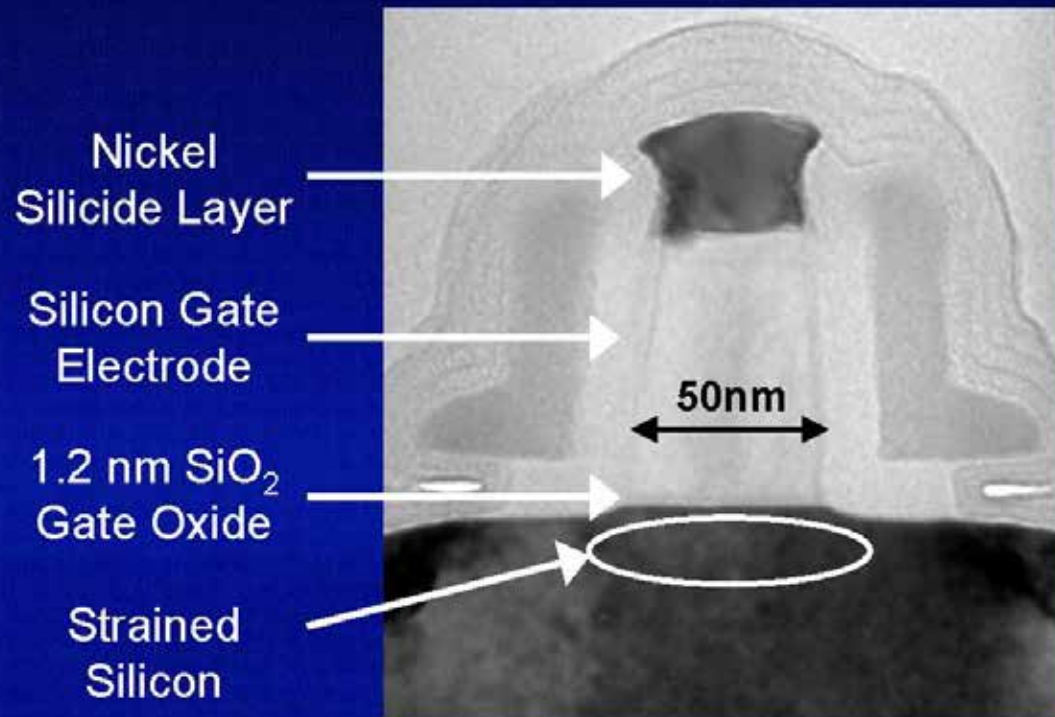
Intel's unique strained silicon technology increases transistor drive current by an average of >30%

intel.

Intel Developer

•Source: Mark Bohr, Intel Corporation

# 90 nm Generation Transistor



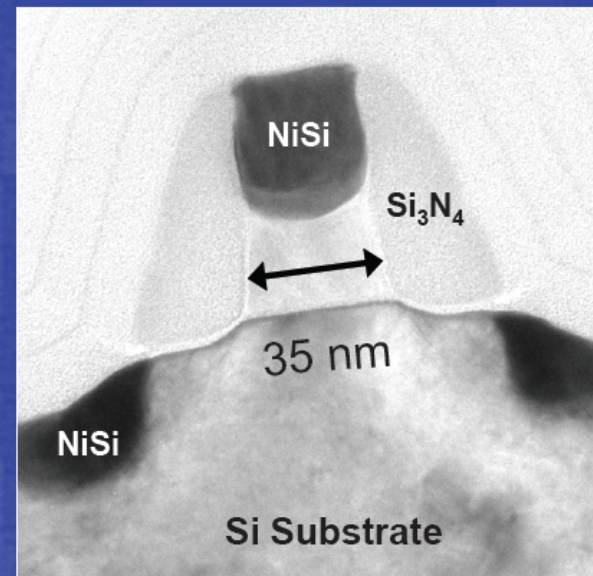
- Strained silicon increases electron/hole mobility.

Intel

• Source: Mark Bohr, Intel Corporation

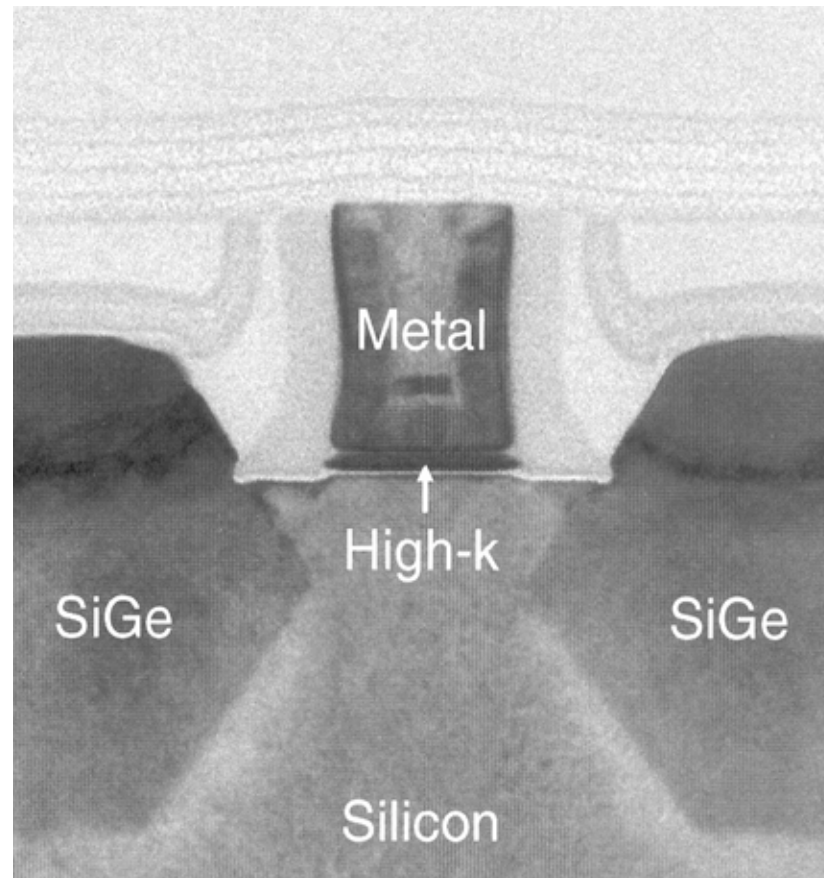
# 65 nm Generation Transistors

- 35 nm gate length
- 1.2 nm gate oxide
- NiSi for low resistance
- 2<sup>ND</sup> generation strained silicon for enhanced performance



# High-K, Metal Gate 45 nm CMOS (Intel)

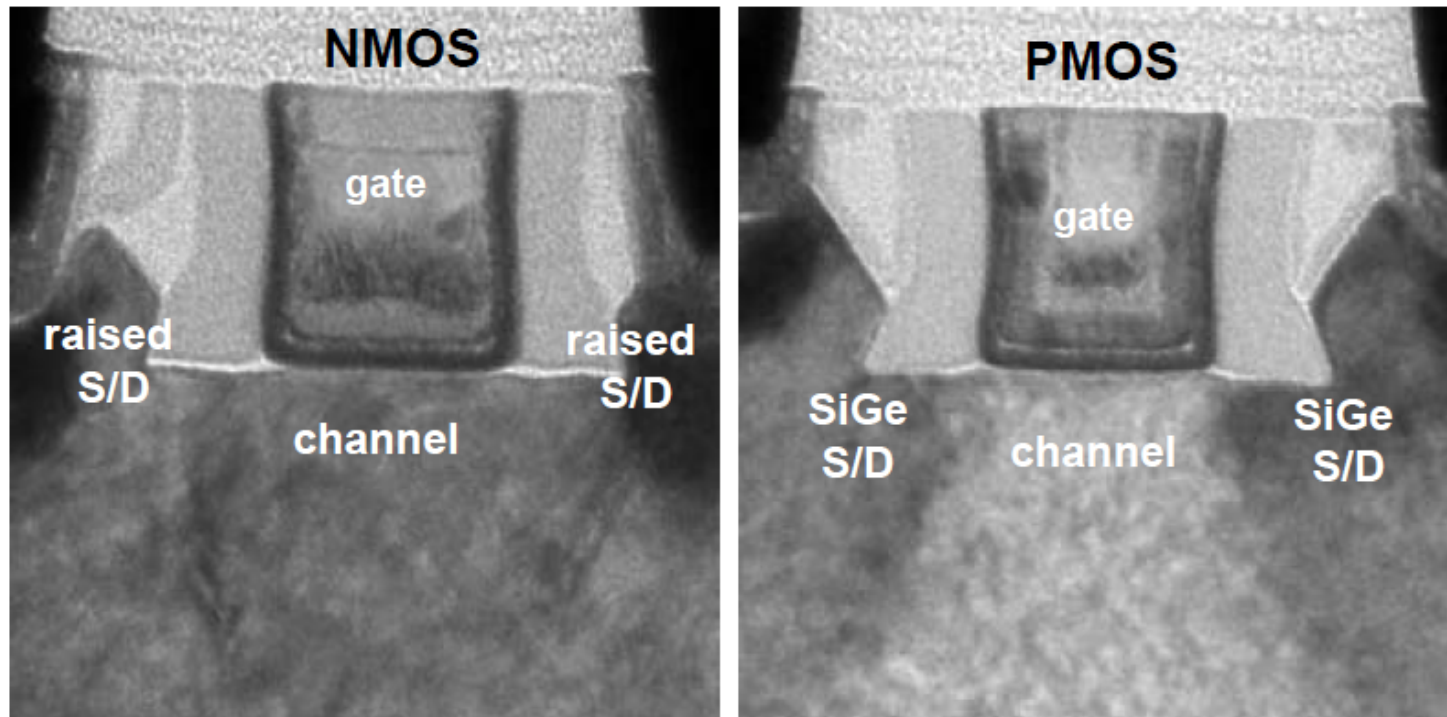
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- K. Mistry, et al., "A 45nm Logic Technology with High-k+ Metal Gate Transistors, Strained Silicon, 9 Cu Interconnect Layers, 193nm Dry Patterning, and 100% Pb-free Packaging", Tech. Digest IEDM, Dec 2007.

# High-K, Metal Gate 32 nm CMOS (Intel)

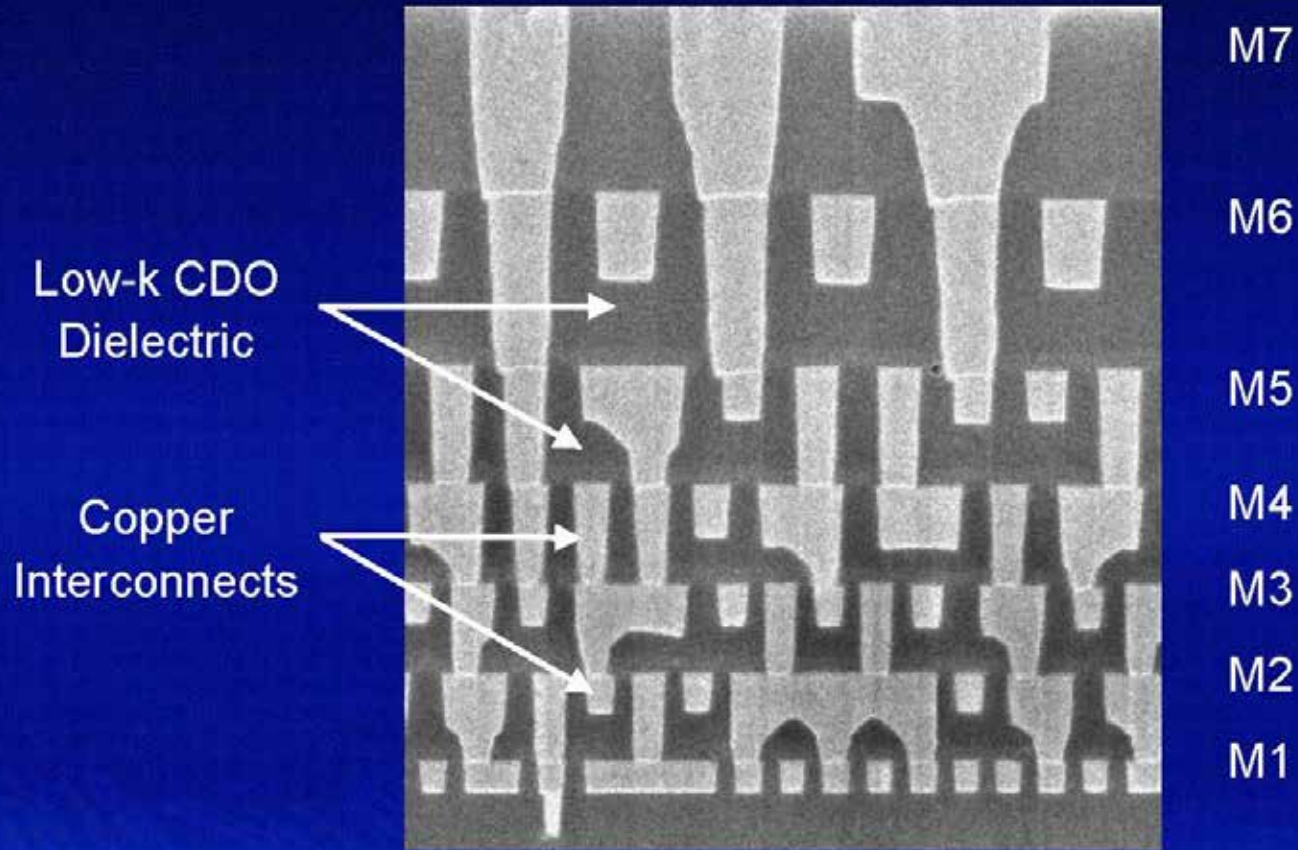
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- P. Packan, et al., "High Performance 32nm Logic Technology Featuring 2nd Generation High-k + Metal Gate Transistors", Tech. Digest IEDM, Dec 2009.

# 90nm INTERCONNECT

## 90 nm Generation Interconnects



7 layers of copper + new low-k CDO dielectric

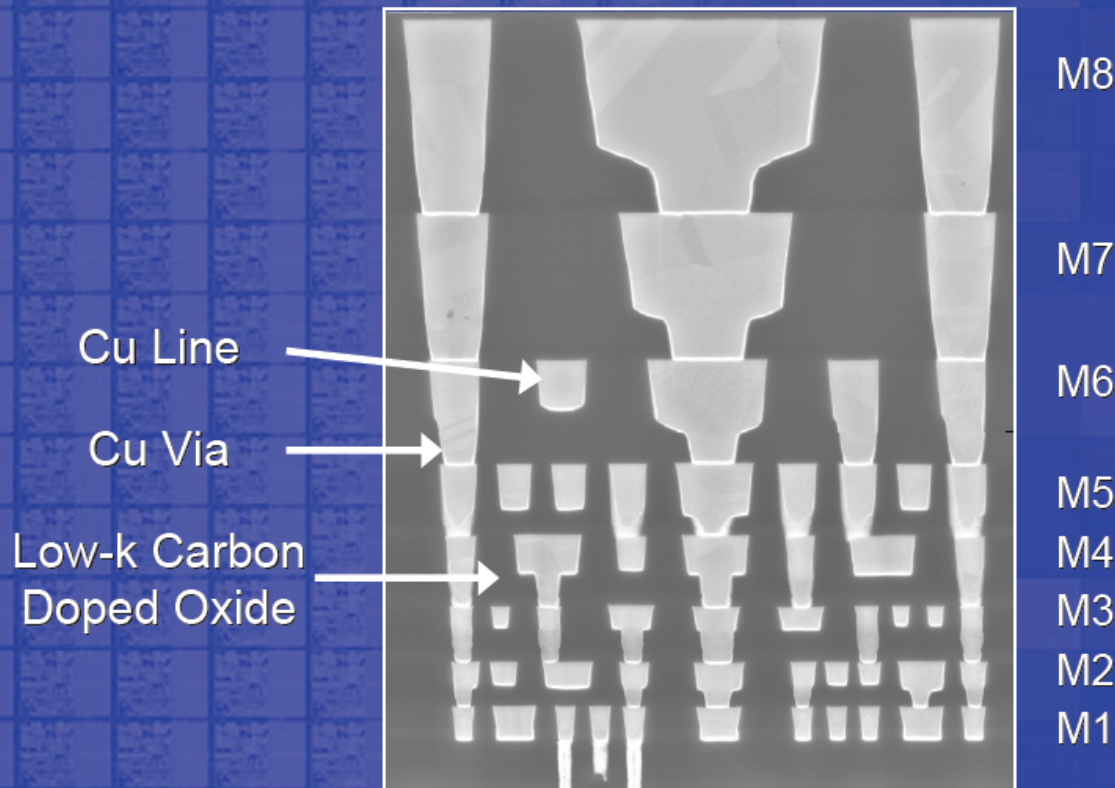
Intel

# 65nm INTERCONNECT

High Performance

13

## 65 nm Generation Interconnects



8 Cu interconnect layers for density and performance  
Low-k CDO dielectric for performance and low power

intel

Intel Developer  
FORUM



# 45nm Interconnect

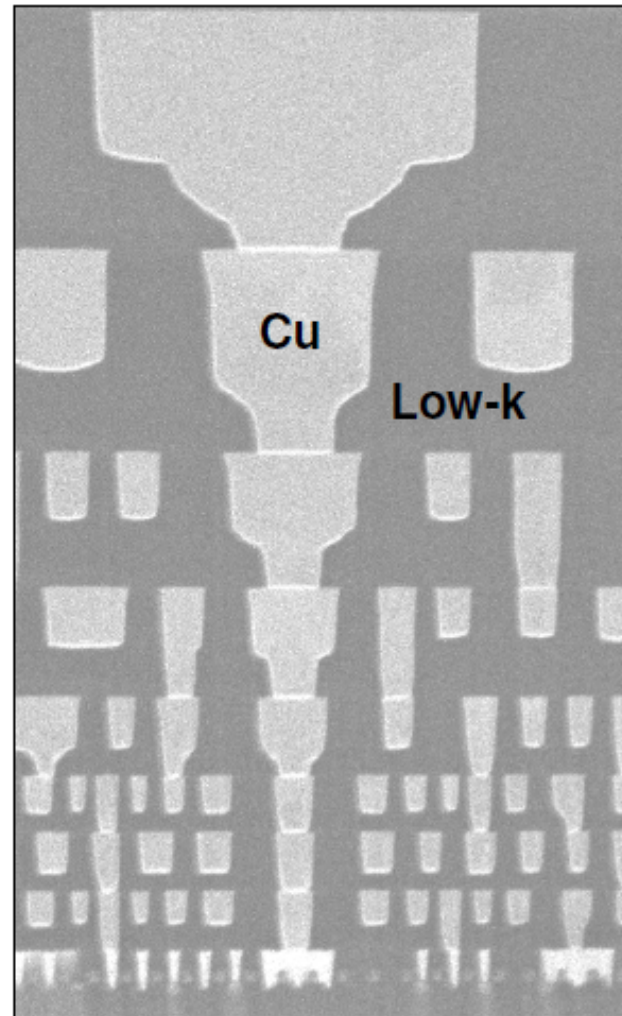
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## Loose pitch + thick metal on upper layers:

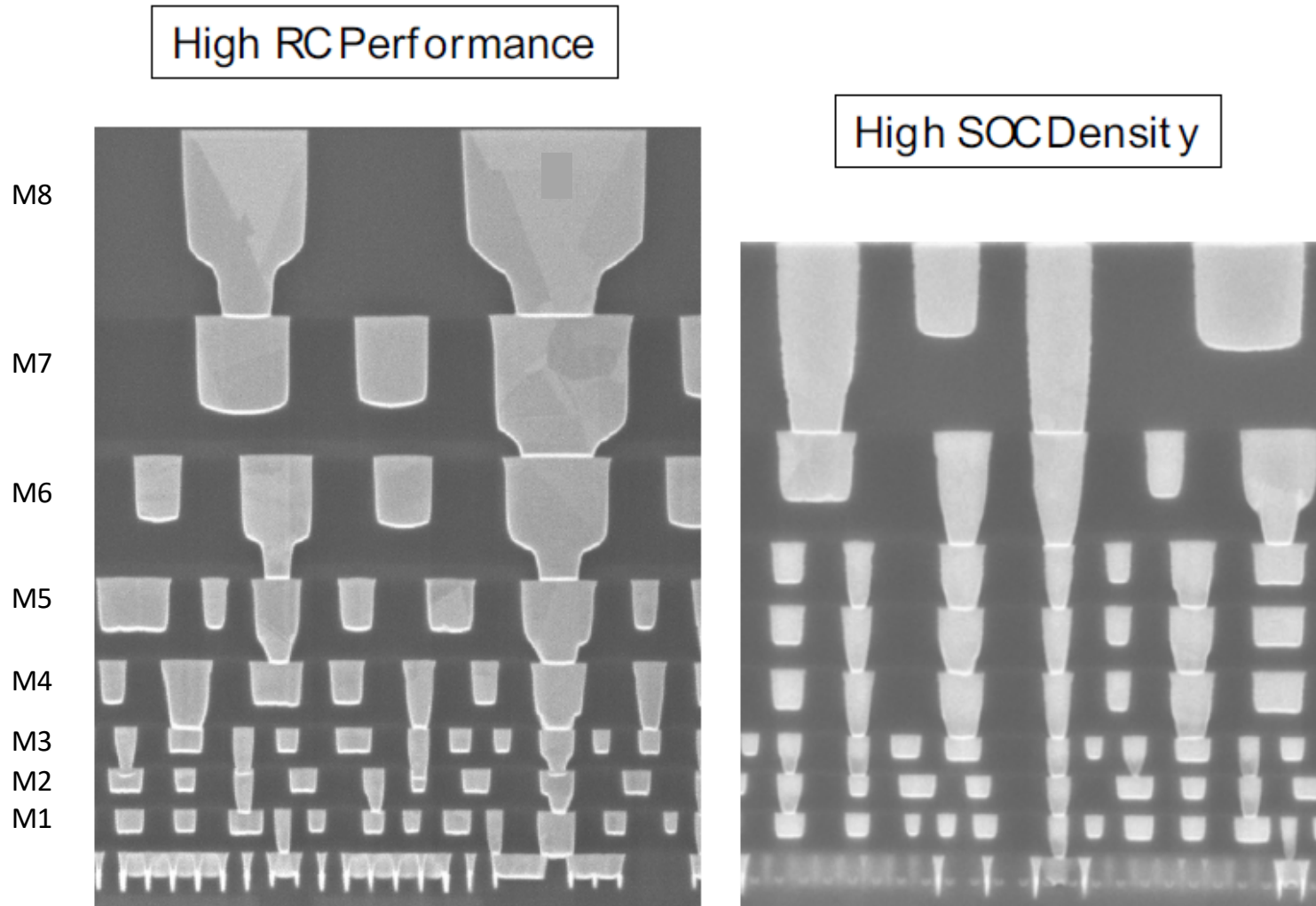
- High speed global wires
- Low resistance power grid

## Tight pitch on lower layers:

- Maximum density for local interconnects



# 32nm Interconnect

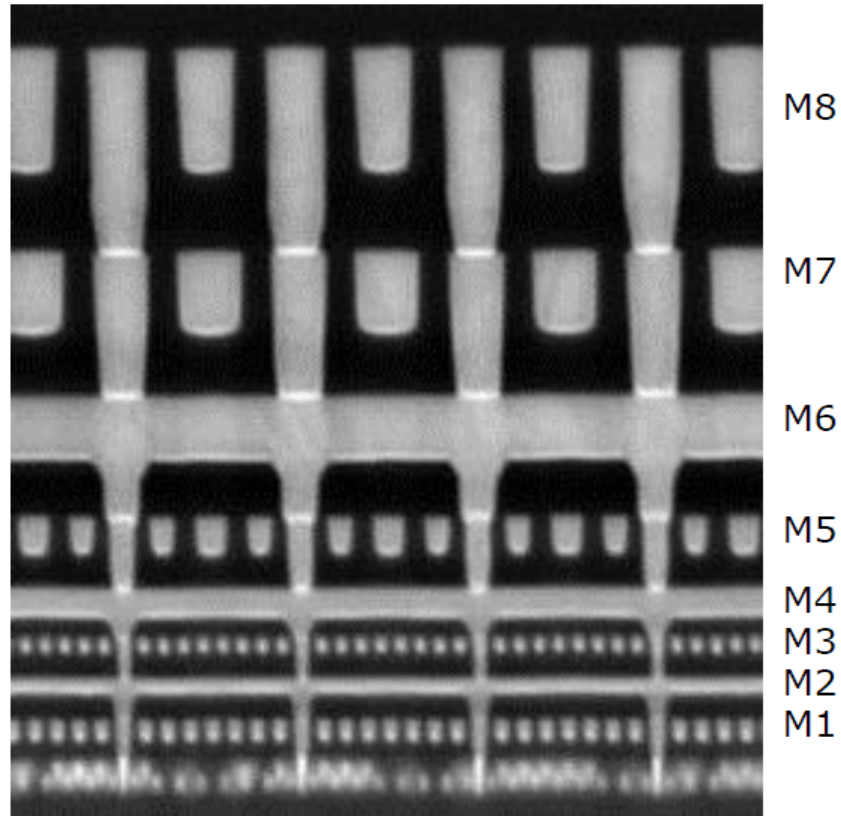


- C.-H. Jan, et al., "A 32nm SoC Platform Technology with 2nd Generation High-k/Metal Gate Transistors Optimized for
- Ultra Low Power, High Performance, and High Density Product Applications", IEDM, Dec 2009.

# 22nm Interconnect

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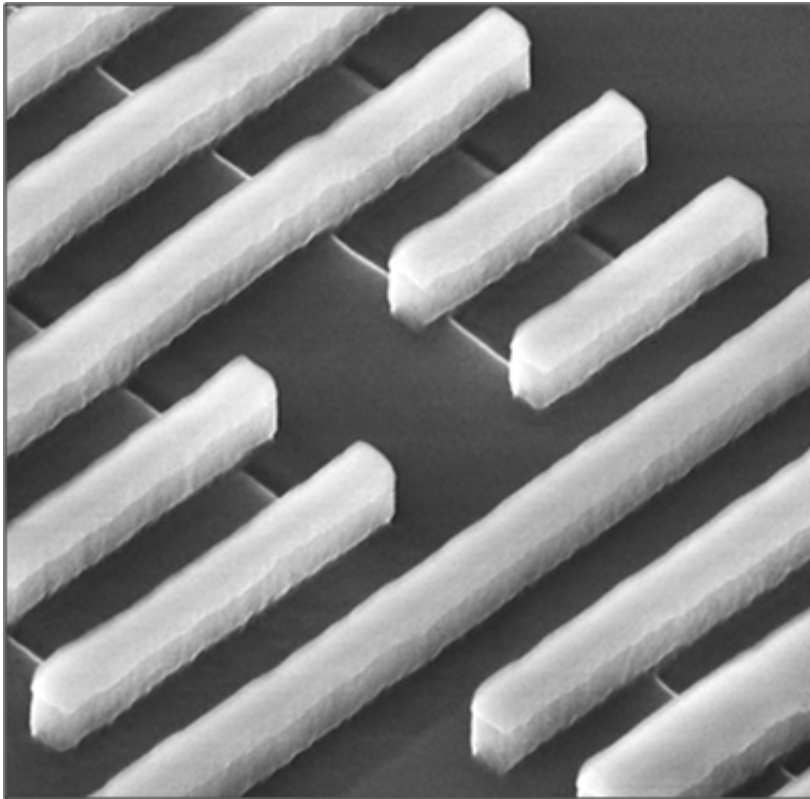
<u>Layer</u>	<u>Pitch</u>
TM	14 $\mu\text{m}$
M8	360 nm
M7	320 nm
M6	240 nm
M5	160 nm
M4	112 nm
M3	80 nm
M2	80 nm
M1	90 nm



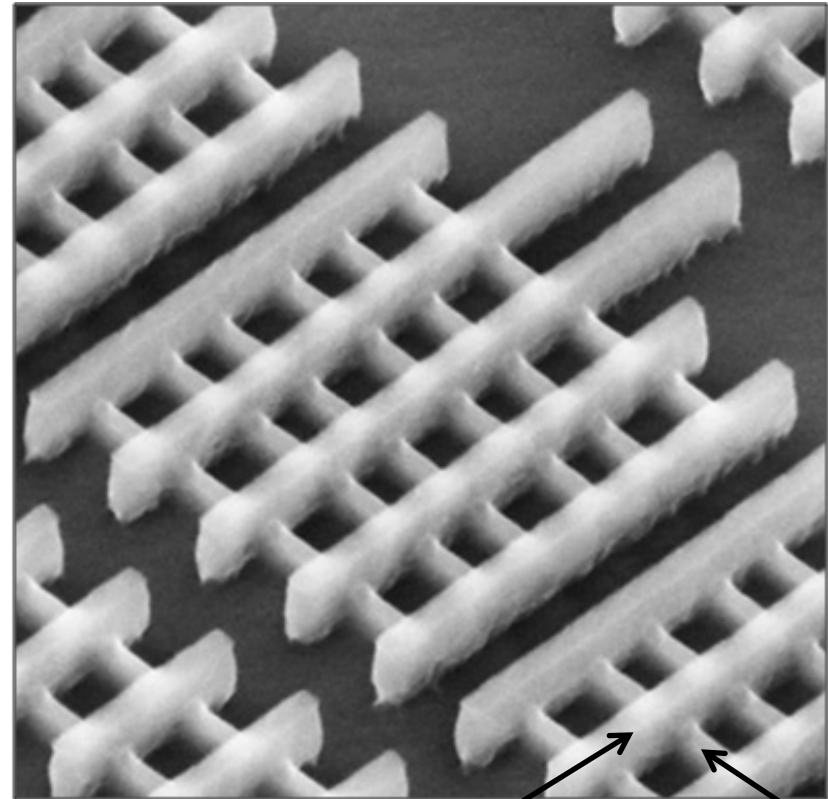
IDF 2012

# FIN-FET Transistor Innovation

32 nm Planar Transistors



22 nm Tri-Gate Transistors



Gates

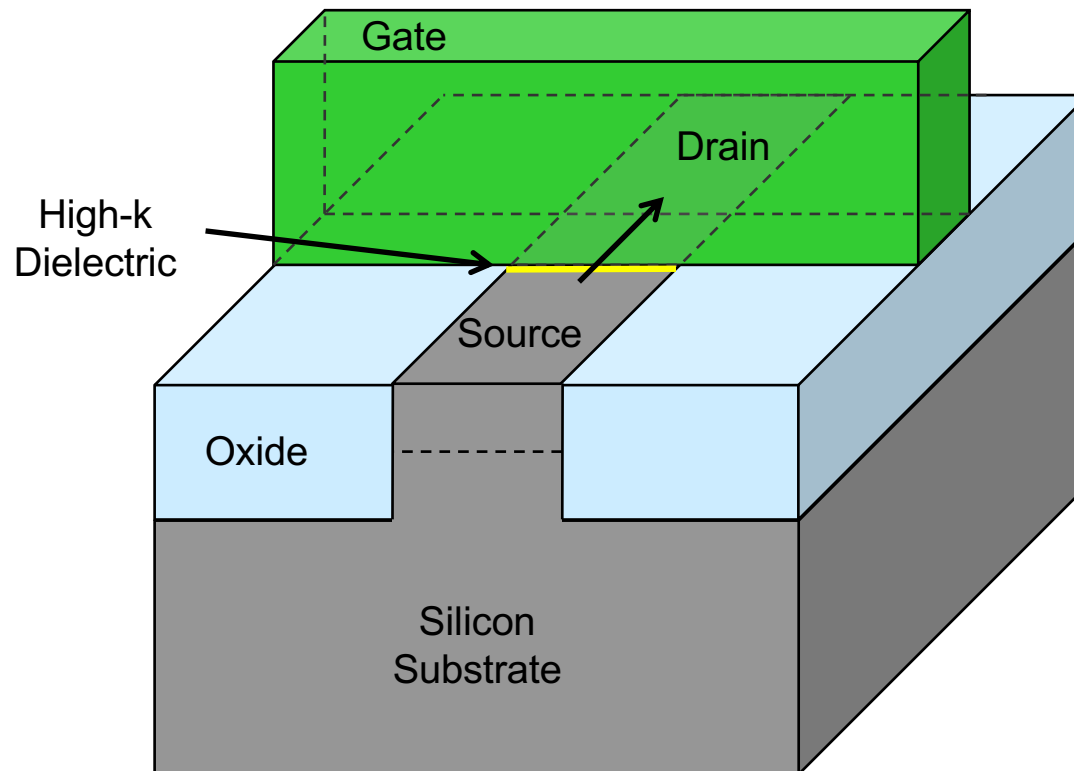
Fins

*Intel's 22 nm technology introduces revolutionary 3-D Tri-Gate transistors*

(courtesy: Mark Bohr, Sr. Intel Fellow)

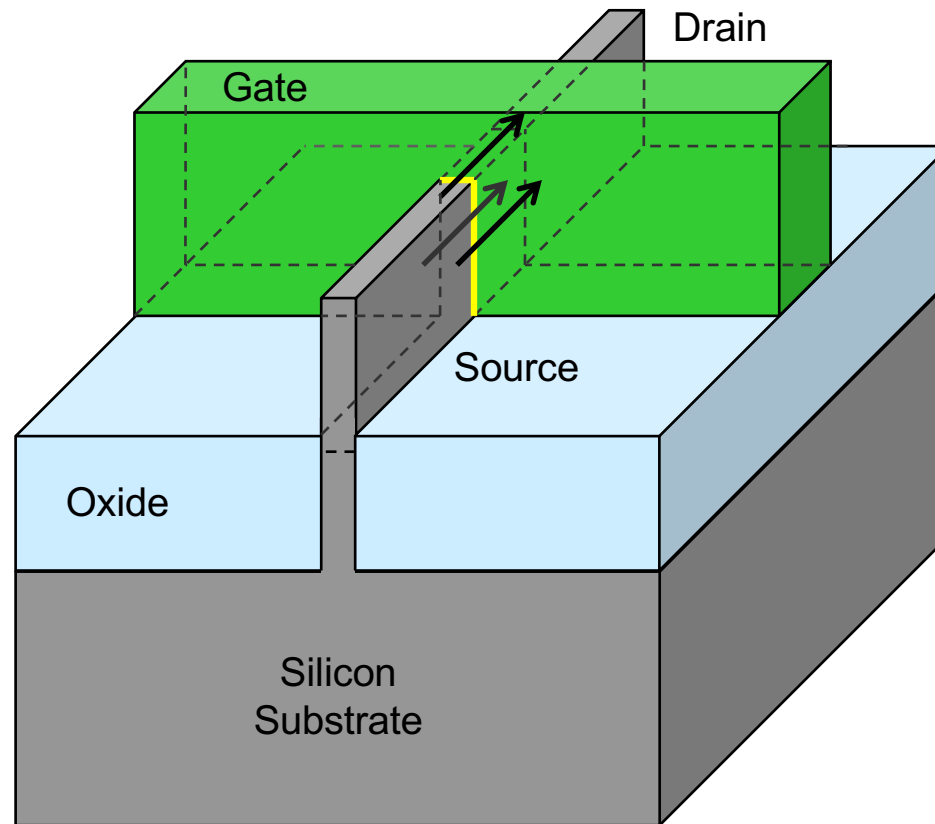
# Traditional Planar Transistor

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***Traditional 2-D planar transistors form a conducting channel on the silicon surface under the gate electrode***

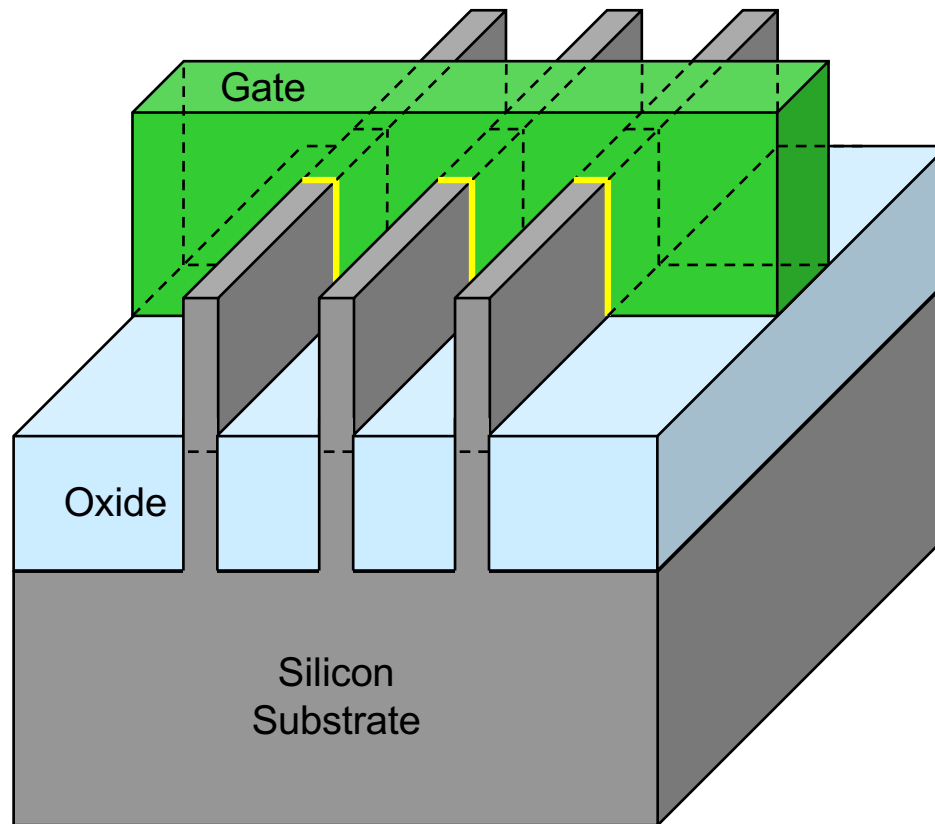
# 22 nm FIN-FET Transistor



***3-D Tri-Gate transistors form conducting channels on three sides of a vertical silicon fin***

# 22 nm FIN-FET Transistor

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***Tri-Gate transistors can connect together multiple fins for higher drive current and higher performance***